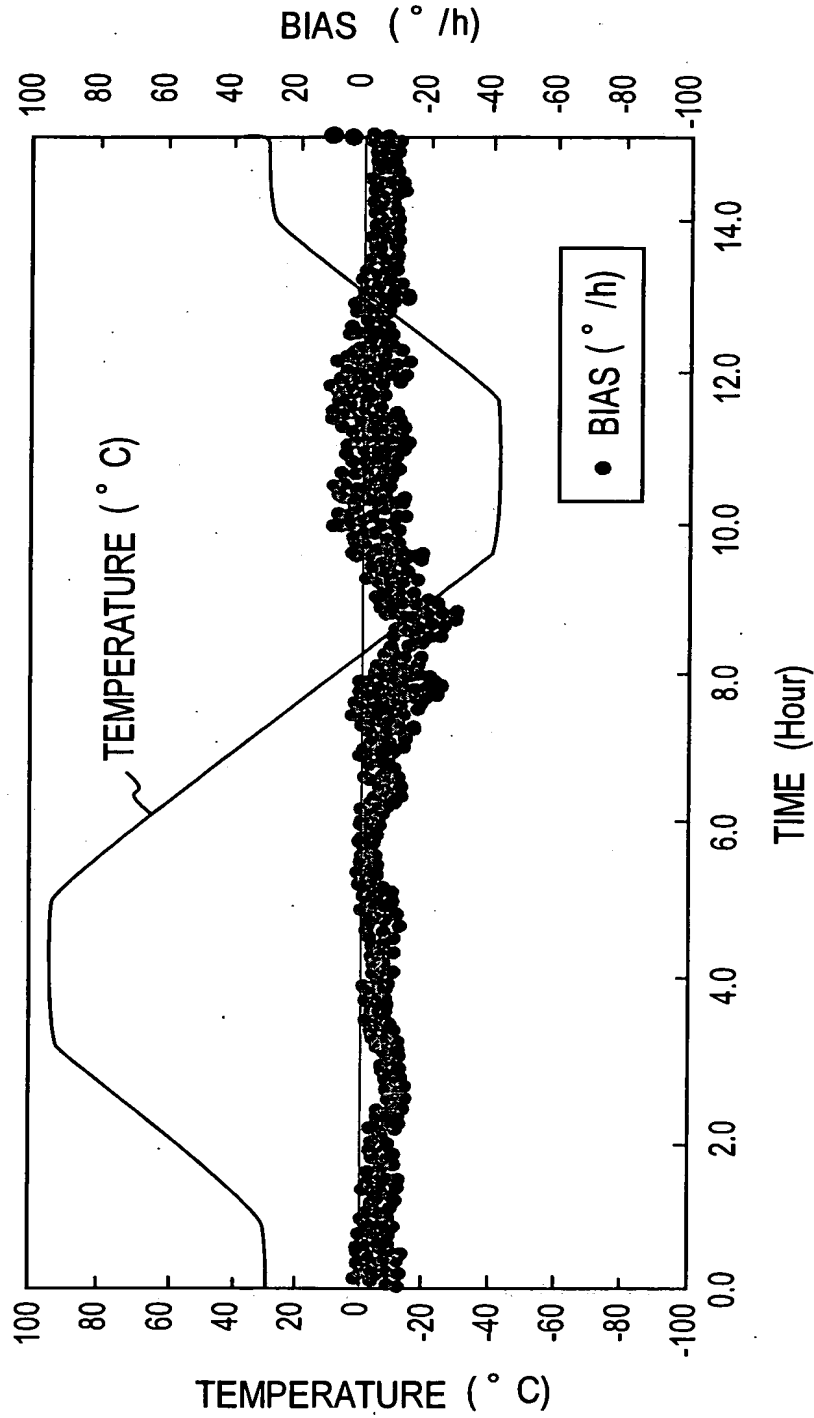


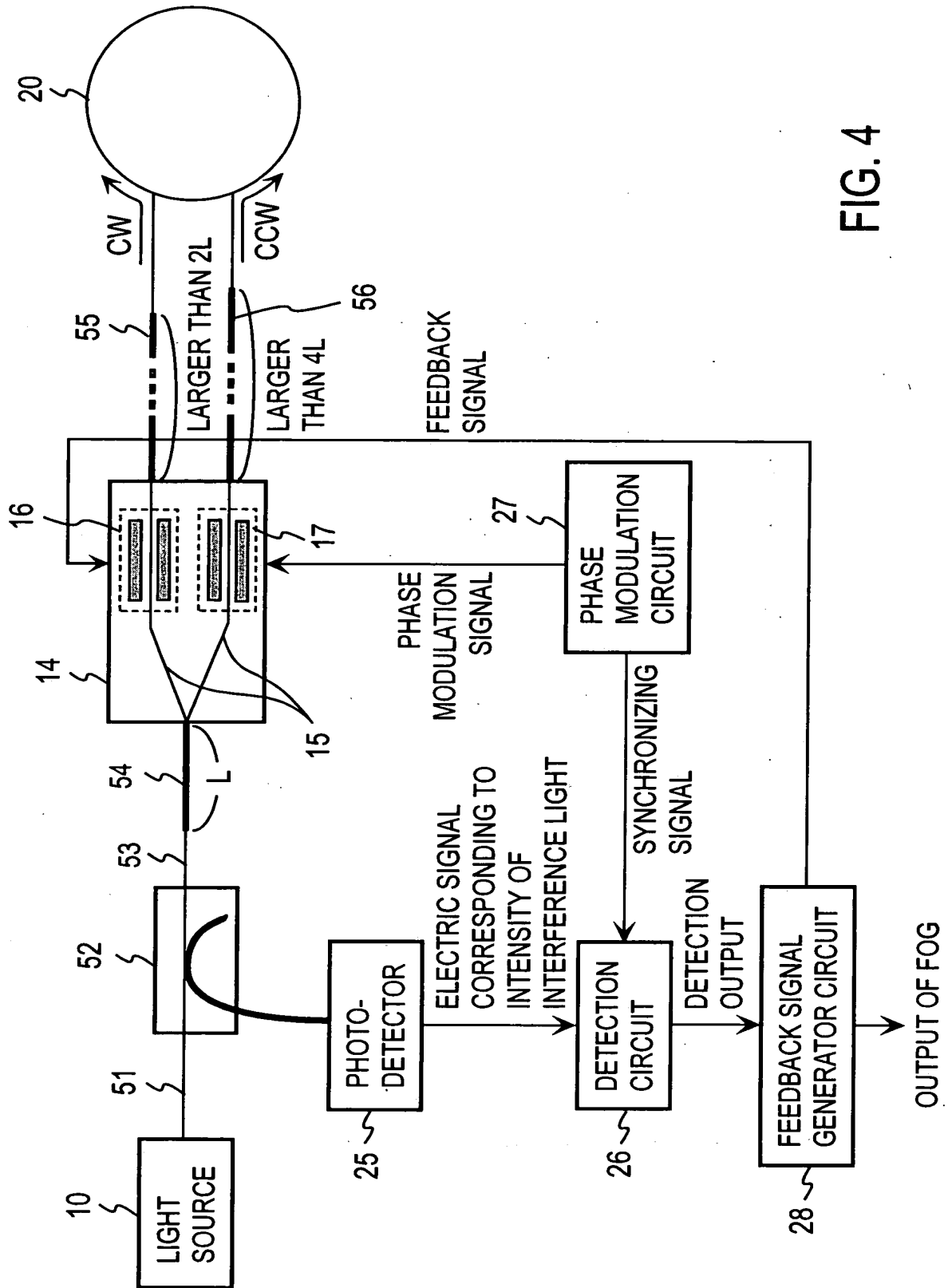
TEMPERATURE TEST IN CASE OPTICAL PATH FROM LIGHT SOURCE TO OPTICAL  
 INTEGRATED CIRCUIT IS FORMED BY SINGLE MODE OPTICAL FIBER

FIG. 2



TEMPERATURE TEST IN CASE ALL OF OPTICAL PATH FROM LIGHT SOURCE TO  
OPTICAL INTEGRATED CIRCUIT IS FORMED BY POLARIZATION MAINTAINING  
OPTICAL FIBER

FIG. 3



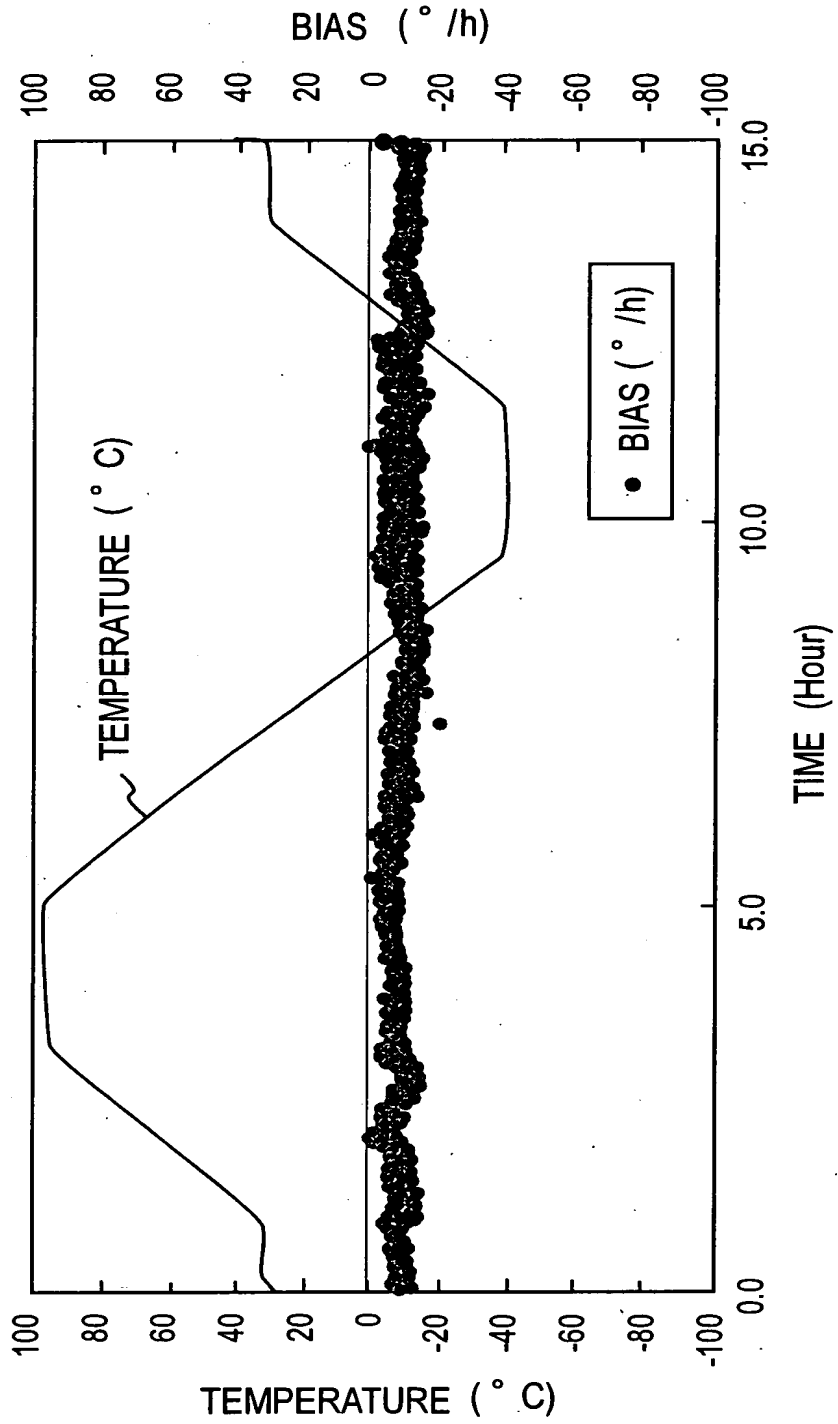
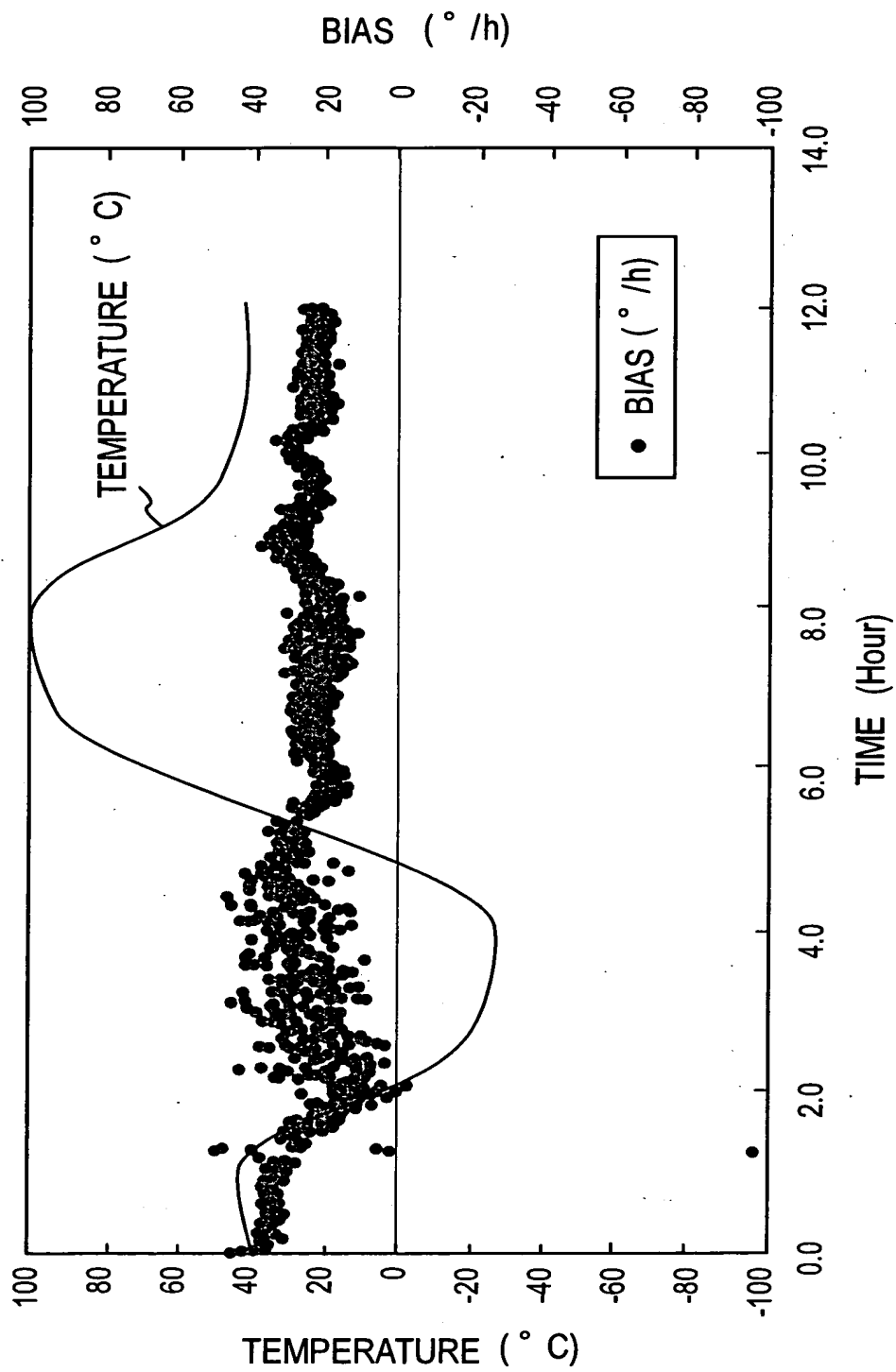


FIG. 5

TEMPERATURE TEST



TEMPERATURE TEST IN CASE A PORTION OF OPTICAL PATH  
 FROM LIGHT SOURCE TO OPTICAL INTEGRATED CIRCUIT IS  
 FORMED BY POLARIZATION MAINTAINING OPTICAL FIBER  
 OF INSUFFICIENT SHORT LENGTH

FIG. 6